

Supplementary Information

Transparent conductive PEDOT-graphene films from large-flake graphite

Figure S1. Control XRD of the PEDOT film

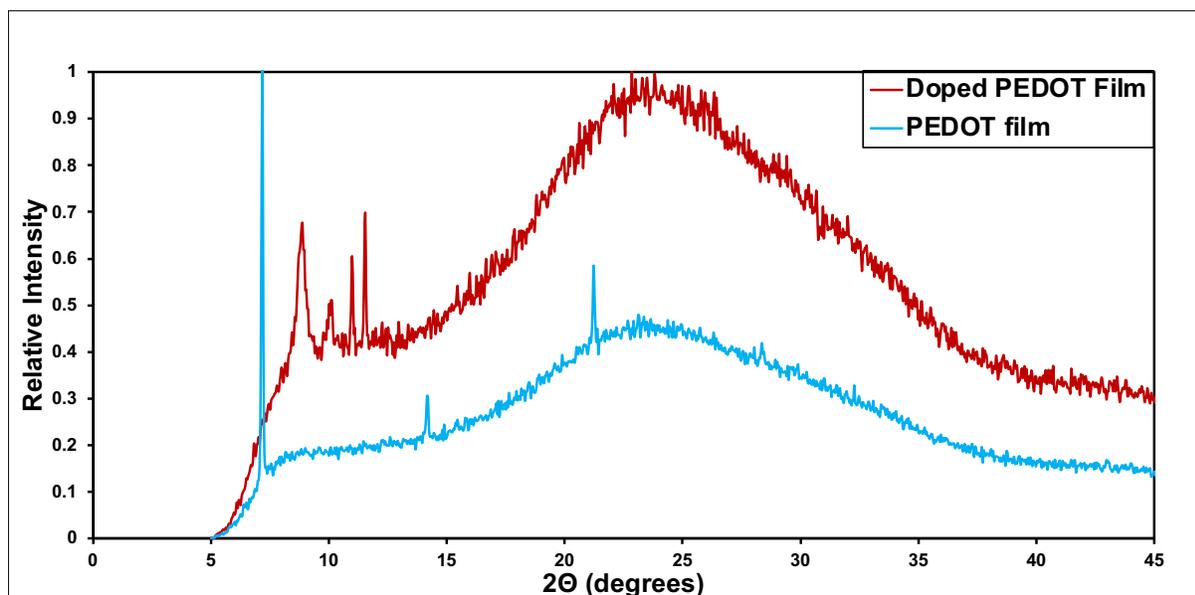
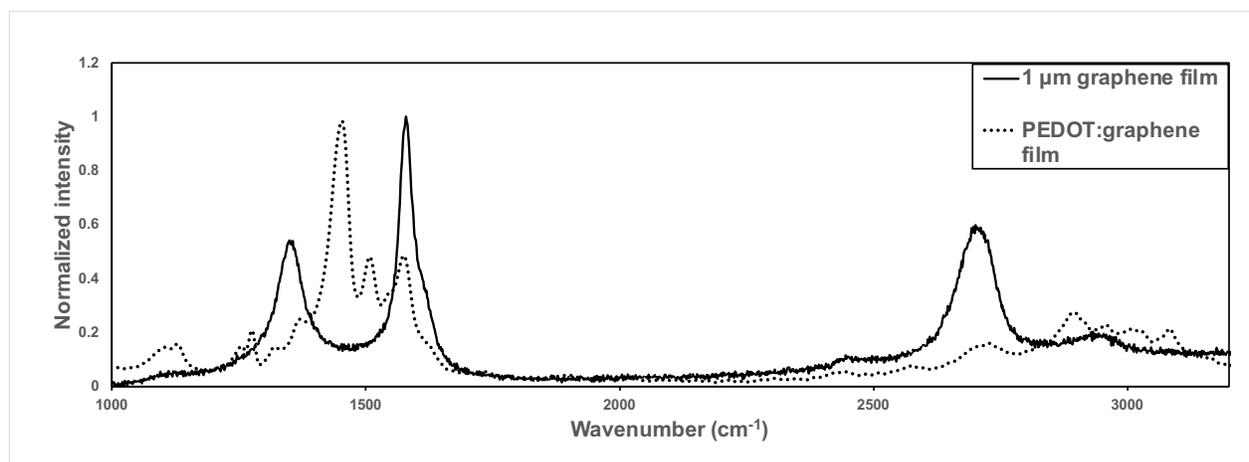


Figure S2. Raman spectra of PEDOT:graphene films



A 1 μm graphene film (solid) compared to the PEDOT: graphene film (dotted). A peak shift is observed at 2,600 cm⁻¹. This is indicative of π-π stacking between PEDOT and graphene.

Figure S3. XPS analysis

Instrument Specs and Info

Instrument Name: K-Alpha ThermoFisher Scientific XPS

Pass Energy: 25.00eV (All high resolution spectra)

Step Size: 0.1 eV (All high resolution spectra)

Beam Diameter: 50 micron

Vacuum Pressure: 1.0×10^{-9} torr (minimum)

Software used for deconvolution: CasaXPS

Scans:

Valence: 50

S2p: 75

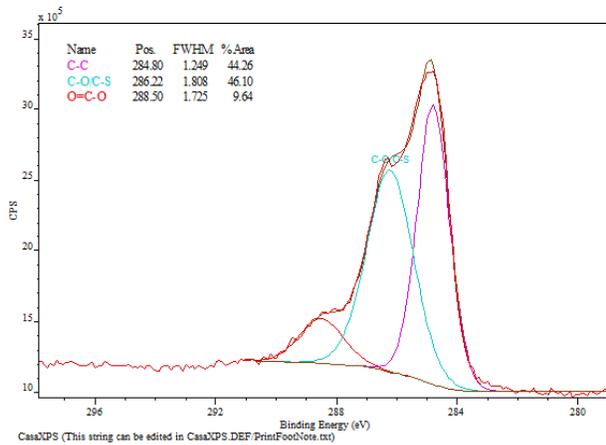
C1s: 50

O1s: 50

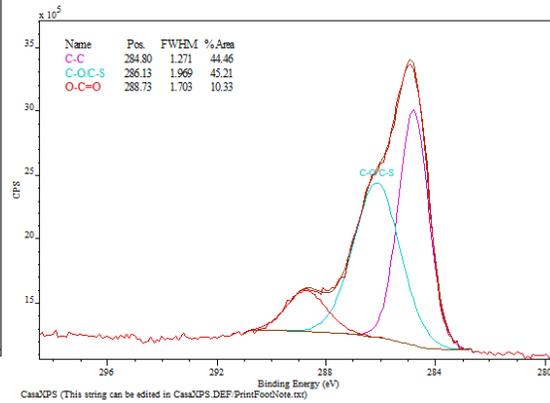
CKLL: 50

Figure S3A. C1s XPS Spectra

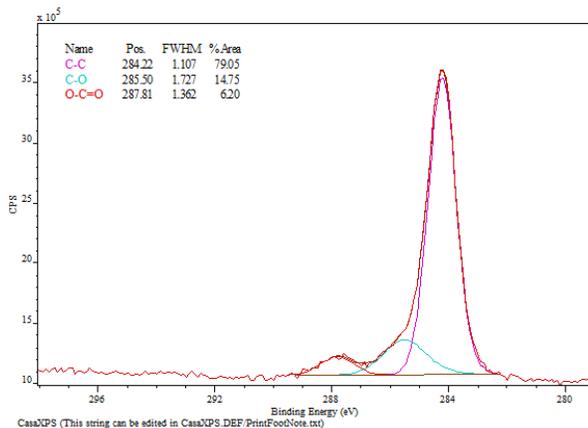
C1s Scan Control



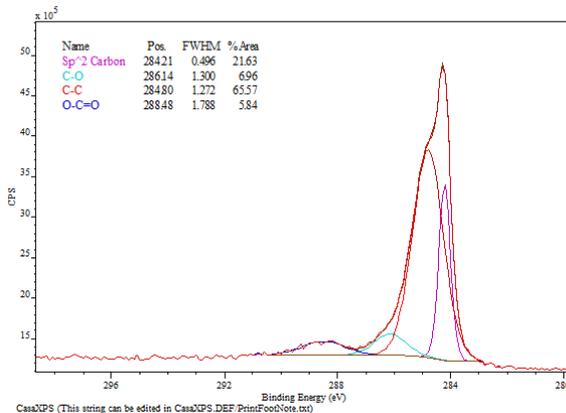
C1s Scan Doped



C1s Scan Graphene



C1s Scan 300Micron Graphene



C1s Scan Graphene Doped

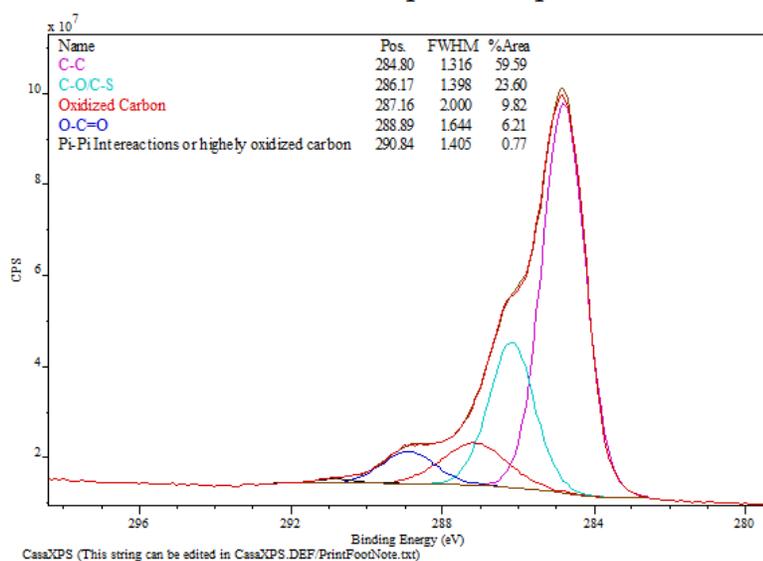
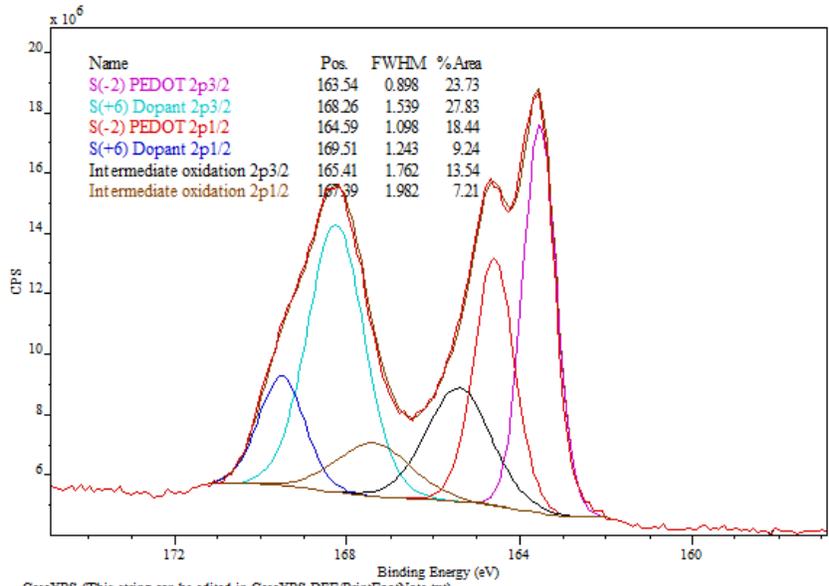
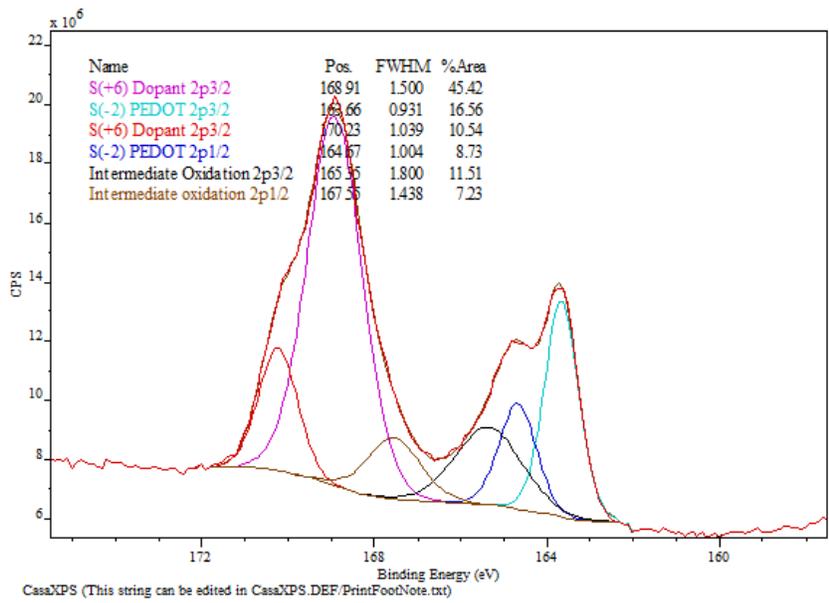


Figure S3B. S2p Scan XPS

S2p Scan Control



S2p Scan Doped



S2p Scan Graphene Doped

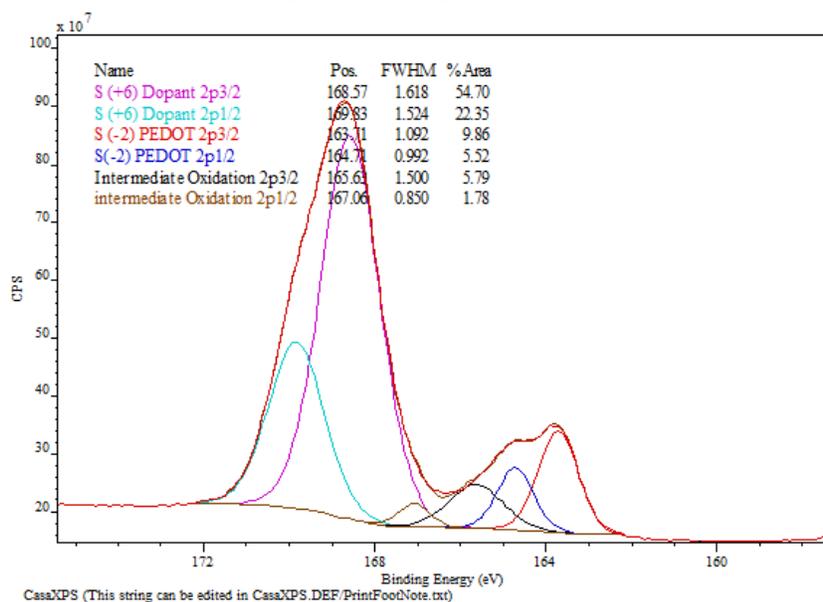


Figure S3C. Si2p

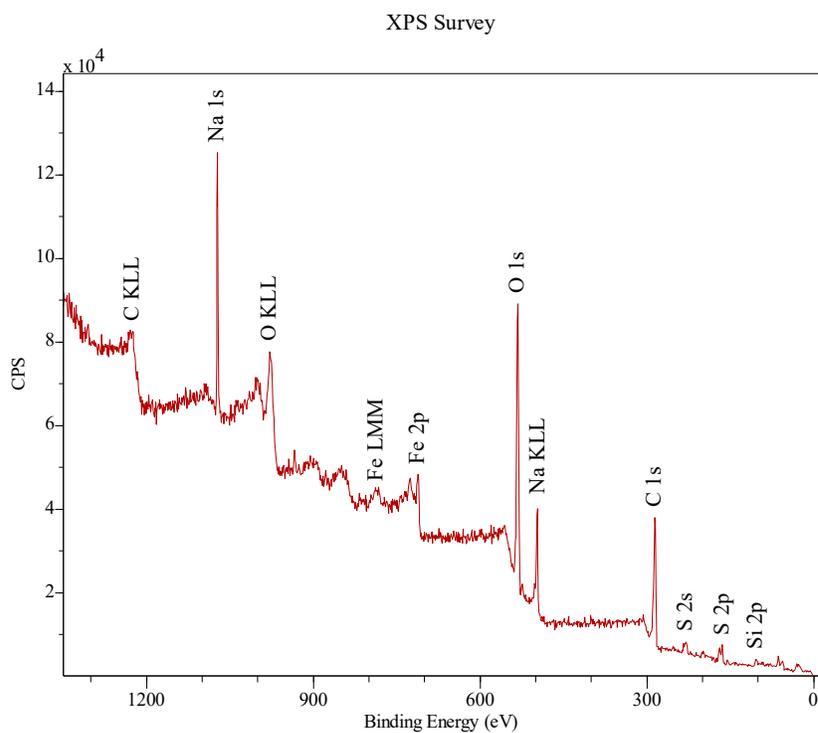


Figure S4. Flake size effect on resistance

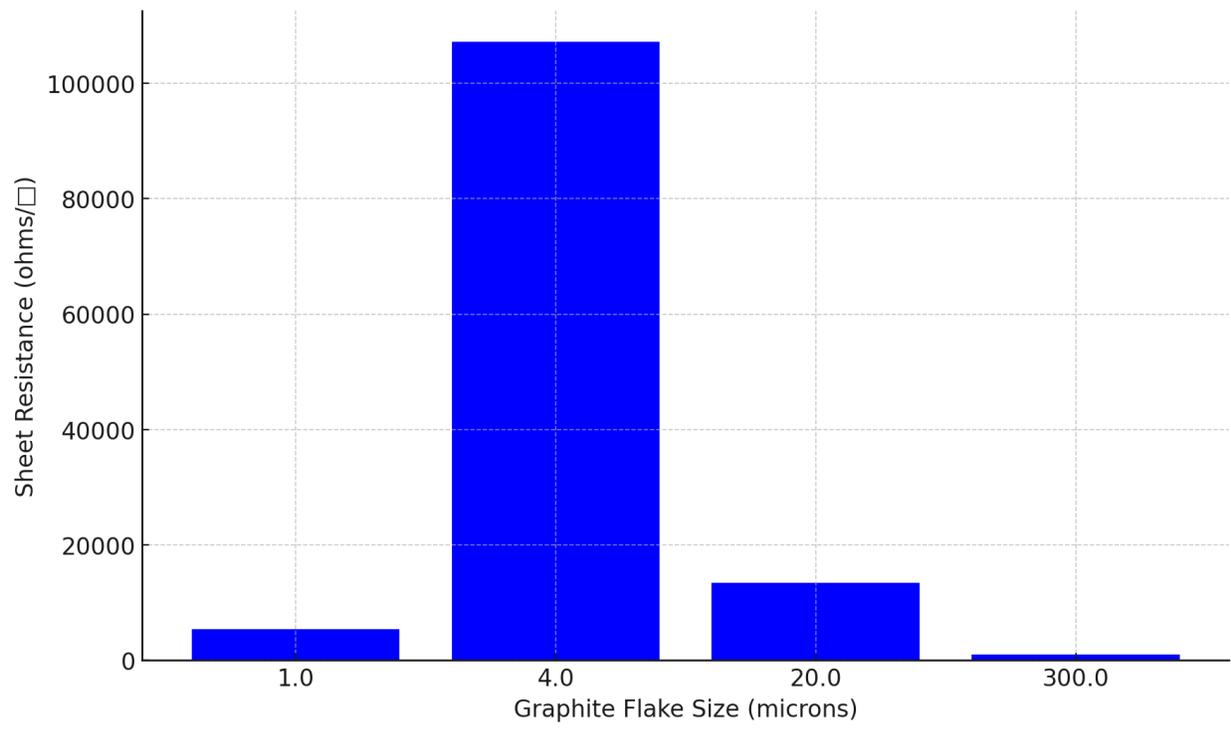


Figure S5. Sensitivity to various stimuli

